				ATTY DOCKET NO. 129/015		SERIAL NO. 10/633130 To be assigned						
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)												
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			U.f	S. PATENT	DOCUMENTS							
*EXAMINER		DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DAT				
SHV		3,958,124	5/18/76	Koch et	Koch et al.		446.11					
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SAV		6,190,062	2/20/01	Subram	nanian et al.	396	3 578					
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		OTHER DOCUME	ENTS (Includin	g Author,	, Title, Date, Pertinent P	Pages, Etc.)						
SHV		Model 682, Precision E	Model 682, Precision Etching Coating System (PECS), Gatan Inc., 2001									
SHV		lon Beam Sputter Depo http://www.southbayted	lon Beam Sputter Deposition and Etching System IBS/e, downloaded from the Internet at http://www.southbaytech.com/cgi-bin/homepage/products/view_product.cfm.									
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.												

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SW		Recent Advances in Broad Ion Beam Techniques/Instrumentation for SEM Specimen Preparation of Semiconductors, Alani R., Mitro, R.J., Hauffe, W., Proceeding from the 25th International Symposium for Testing and Failure Analysis, November 1999									
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